

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

AKRAM ALI SALMAN  
XUEJUN ZHAO  
KURT O. TAYLOR  
STEPHEN G. BEEBE

Group Art Unit: Unknown

Examiner: Unknown

Attorney Docket: 2000.111200/H2022

Customer No.: 23720

Serial No.: Unknown

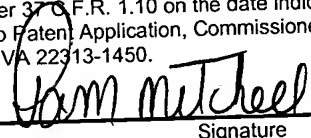
Filed: Concurrently Herewith

For: METHOD FOR DETERMINING THE  
RELIABILITY OF DIELECTRIC LAYERS

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

EXPRESS MAIL RECEIPT	
NUMBER:	EV 291395941 US
DATE OF DEPOSIT:	September 18, 2003
I hereby certify that this paper or fee is being deposited with the United States Postal Service "EXPRESS MAIL POST OFFICE TO ADDRESSEE" service under 37 C.F.R. 1.10 on the date indicated above and is addressed to: Mail Stop Patent Application, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.	
	
Signature	

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed documents required by 37 C.F.R. § 1.98(a)(2) are enclosed for the convenience of the Examiner.

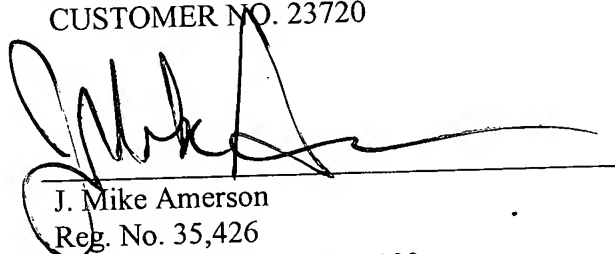
In accordance with 37 C.F.R §§ 1.97(g),(h), this Information Disclosure Statement is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that the information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b).

The present Information Disclosure Statement is being filed prior to the receipt of a first Official Action reflecting an examination on the merits, and hence is believed to be timely filed in accordance with 37 C.F.R § 1.97(b). No fees are believed to be due in connection with the filing of this Information Disclosure Statement, however, should any fees under 37 C.F.R. §§ 1.16 to 1.21 be deemed necessary for any reason relating to these materials, the Assistant Commissioner is hereby authorized to deduct said fees from Williams, Morgan & Amerson, P.C., Deposit Account No. 50-0786/2000.111200.

Applicants respectfully request that the listed documents be made of record in the present case.

Respectfully submitted,

WILLIAMS, MORGAN & AMERSON  
CUSTOMER NO. 23720

A handwritten signature in black ink, appearing to read "J. Mike Amerson", is written over a horizontal line.

Date: September 18, 2003

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Form PTO-1449 (modified)		Atty. Docket No. 2000.111200/H2022	Serial No. Unknown
List of Patents and Publications for Applicant's  INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		Applicant Akram Ali Salman, Xuejun Zhao, Kurt O. Taylor and Stephen G. Beebe	
		Filing Date: September 18, 2003	Group: Unknown
U.S. Patent Documents <i>See Page 1</i>	Foreign Patent Documents <i>See Page 1</i>	Other Art <i>See Page 1</i>	

### U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
	A1						
	A2						
	A3						

### Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						
	B2						
	B3						

### Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	Salman <i>et al.</i> , "Gate Dielectric Breakdown and Latent Failures of Ultrathin (~13A) DPN under Pulsed Stress in Partially Depleted SOI MOSFETs"
	C2	Wu <i>et al.</i> , "Breakdown and Latent Damage of Ultra-Thin Gate Oxides under ESD Stress Conditions," EOS/ESD Symposium 00-287-295
	C3	Montoya <i>et al.</i> , "A Study of the Mechanisms for ESD Damage to Reticles," EOS/ESD Symposium 00-394-405
	C4	Hunter, "The Analysis of Oxide Reliability Data," 98 IRW Final Report, 114-34
	C5	Linder <i>et al.</i> , "Growth and Scaling of Oxide Conduction after Breakdown," 2003 IEEE, 402-05
	C6	Alam and Smith, "A Phenomenological Theory of Correlated Multiple Soft-Breakdown Events in Ultra-Thin Gate Dielectrics," 2003 IEEE, 406-411

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.